

Claim 28 (New)

Sub B7
A method for aligning the optical beam path of a microscope, having a light source (1), a microscope optical system, a detection stop (12) defining a first optical reference plane, and a detection device (13), wherein the method comprises the steps of:

- A1
- a) providing the plane of the detection stop (12) as a first optical reference plane;
 - and
 - b) providing a second reference plane wherein an entire beam path is defined as perpendicular to said first optical reference plane and said second optical reference plane and through a center of said detection stop.

Claim 29 (New)

The method as defined in Claim 1, characterized in that all optical elements are aligned with respect to the reference planes.

Claim 30 (New)

A microscope assemblage, having a light source (1), a microscope optical system, a detection device (13), a detection stop (12) defining a first optical reference plane and a second reference plane wherein an entire beam path is defined as perpendicular to said first optical reference plane and said second optical reference plane and through a center of said detection stop.

Claim 31 (New)

The method as defined in Claim 30, characterized in that all optical elements are alignable with respect to the reference planes.

Please amend Claims 1, 4-6, 12, 19-21, and 27 as follows:

Claim 1 (Amended)

#13 Subt. B0
A method for aligning the optical beam path of a microscope, having a light source (1), a microscope optical system, a detection stop (12), and a detection device (13), wherein the method comprises the steps of:

- a) providing a center of the detection stop (12) as a first optical reference point; and
- b) providing a second optical reference point wherein an entire beam path is defined by said first optical reference point and said second optical reference point.

Claim 4 (Amended)

The method as defined in Claim 28, characterized in that the planes are Fourier planes.

A3
Claim 5 (Amended)

The method as defined in Claim 1, characterized in that the second reference point is at a center of an objective pupil (9).

Claim 6 (Amended)

The method as defined in Claim 1, characterized in that all optical elements are aligned with respect to the reference points.

Subt. B3
#13
Claim 12 (Amended)

A microscope assemblage, having a light source (1), a microscope optical system, a detection device (13), a detection stop (12) defining a first optical reference point and a second optical reference point wherein an entire beam path is defined by said first optical reference point and said second optical reference point.

A5
Claim 19 (Amended)

The method as defined in Claim 30, characterized in that the planes are Fourier planes.